

INDUCTIVE LOAD TESTER (Included leakage current test) リーク電流測定機能付きL負荷テスター

LVNI20ZFCA 150V 200A

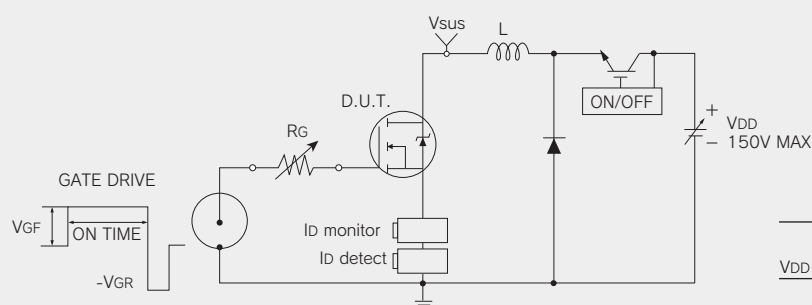
NEW

●LVNI20ZFCA is inductive load tester for MOS-FET, which system is for a measurement with a wafer condition. This system is equipped with high speed interception circuits at a chip destruction, and has IGSS and IDSS measurement circuits for leakage measurement before and after L load measurement.

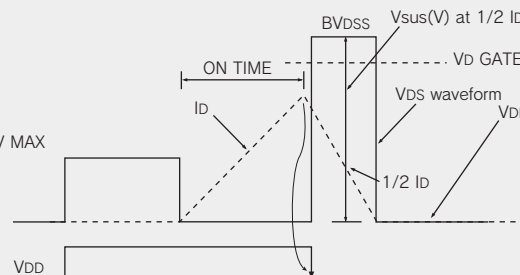
●LVNI20ZFCAは、MOS-FET専用のL負荷試験器で、ウェハ状態での測定に対応したシステム構成となっています。チップ破壊時の高速遮断回路を装備するとともに、IGSS、IDSSの測定回路を実装しており、L負荷試験前後のリーク測定も可能としています。



Test Circuit



Measurement Waveform

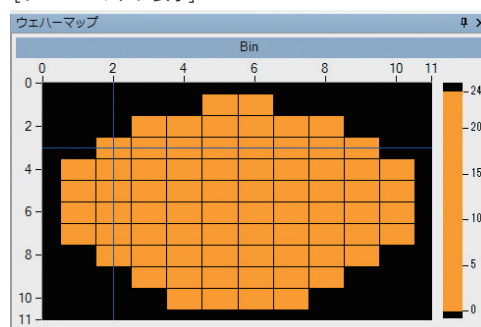


Turn off VDD power supply after reaching to the setting current value.
設定電流到達後、VDD電源をOFFにする。

MODEL		LVNI20ZFCA	
SETTING RANGE			
MEASURABLE DEVICES		NPN/PNP	
ID/IL	±0.20A~±9.99A	0.01A STEP	
	±02.0A~±99.9A	0.1A STEP	
	±020A~±200A	1A STEP	
VDD	±001V~±150V	1V STEP	
VGF	±00.1V~±20.0V	0.1V STEP	
VGR	±00.1V~±20.0V	0.1V STEP	
REPEAT	1~19		
ON TIME	0.0000ms~2.0000ms	0.1 μs STEP	
DET-DELAY	0.1 μs~ 9.9 μs	0.1 μs STEP	
V-GATE	0001A~3000A	1A STEP	
Rg	6 circuit select is possible		
BINNING			
BIN INDICATION	PASS, PRE-FAIL, POST-FAIL, Vd-FAIL, Id-ERROR, SELF-FAIL		
DIMENSIONS & WEIGHT			
MAIN UNIT	500(W)×800(D)×900(H)…130kg		
HEAD BOX	430(W)×700(D)×245(H)…32kg		

[Wafer map display]

[ウエハマップ表示]



LEAKAGE CURRENT

SETTING RANGE		
IDSS	Voltage(VDs) : 0.01V~99.9V	Current : 00.00nA~99.99 μA
IGSS	Voltage(VGs) : 0.01V~99.9V	Current : 00.00nA~99.99 μA